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APPLICATION NO.	FILING DATE	FIRST NAMED INVENTOR	ATTORNEY DOCKET NO.	CONFIRMATION NO.	
10/595,640	05/02/2006	Toshihide Tsubata	70404.90/ma	3891	
	7590 06/04/200 SHIKI KAISHA	8	EXAMINER		
	& BENNETT, LLP	TAYLOR, EARL N			
8180 GREENSBORO DRIVE SUITE 850			ART UNIT	PAPER NUMBER	
MCLEAN, VA	22102		2818		
			NOTIFICATION DATE	DELIVERY MODE	
			06/04/2008	ELECTRONIC	

Please find below and/or attached an Office communication concerning this application or proceeding.

The time period for reply, if any, is set in the attached communication.

Notice of the Office communication was sent electronically on above-indicated "Notification Date" to the following e-mail address(es):

JKEATING@KBIPLAW.COM uspto@kbiplaw.com

Advisory Action Before the Filing of an Appeal Brief

Application No.	Applicant(s)		
10/595,640	TSUBATA ET AL.		
Examiner	Art Unit		
EARL N. TAYLOR	2818		

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The MAILING DATE of this communication appe	ars on the cover sheet with the c	correspondence add	ress
THE REPLY FILED <u>05 May 2008</u> FAILS TO PLACE THIS APPI	LICATION IN CONDITION FOR AL	LOWANCE.	
1. The reply was filed after a final rejection, but prior to or on application, applicant must timely file one of the following application in condition for allowance; (2) a Notice of Apper for Continued Examination (RCE) in compliance with 37 C periods:	replies: (1) an amendment, affidavireal (with appeal fee) in compliance	t, or other evidence, w with 37 CFR 41.31; or	hich places the (3) a Request
a) The period for reply expires 3 months from the mailing date b) The period for reply expires on: (1) the mailing date of this A no event, however, will the statutory period for reply expire to Examiner Note: If box 1 is checked, check either box (a) or (MONTHS OF THE FINAL REJECTION. See MPEP 706.07(f Extensions of time may be obtained under 37 CFR 1.136(a). The date of	dvisory Action, or (2) the date set forth ater than SIX MONTHS from the mailing b). ONLY CHECK BOX (b) WHEN THE ').	g date of the final rejection FIRST REPLY WAS FII	on. LED WITHIN TWO
have been filed is the date for purposes of determining the period of ext under 37 CFR 1.17(a) is calculated from: (1) the expiration date of the s set forth in (b) above, if checked. Any reply received by the Office later may reduce any earned patent term adjustment. See 37 CFR 1.704(b). NOTICE OF APPEAL	ension and the corresponding amount of hortened statutory period for reply origi	of the fee. The appropria nally set in the final Office	ate extension fee e action; or (2) as
 The Notice of Appeal was filed on A brief in comp filing the Notice of Appeal (37 CFR 41.37(a)), or any exter Notice of Appeal has been filed, any reply must be filed wi AMENDMENTS 	nsion thereof (37 CFR 41.37(e)), to	avoid dismissal of the	
The proposed amendment(s) filed after a final rejection, because it is a final rejection, because the final rejection, because the final rejection, because it is a final rejection in beta final rejection.	nsideration and/or search (see NOT w);	TE below);	
appeal; and/or (d) They present additional claims without canceling a converse NOTE: (See 37 CFR 1.116 and 41.33(a)).	corresponding number of finally reje	ected claims.	
4. The amendments are not in compliance with 37 CFR 1.12 5. Applicant's reply has overcome the following rejection(s):		mpliant Amendment (l	PTOL-324).
6. Newly proposed or amended claim(s) would be all non-allowable claim(s).	·	•	-
7. For purposes of appeal, the proposed amendment(s): a) [how the new or amended claims would be rejected is prov The status of the claim(s) is (or will be) as follows: Claim(s) allowed:		l be entered and an e	xpianation of
Claim(s) allowed: Claim(s) objected to: Claim(s) rejected: Claim(s) withdrawn from consideration: AFFIDAVIT OR OTHER EVIDENCE			
 The affidavit or other evidence filed after a final action, but because applicant failed to provide a showing of good and was not earlier presented. See 37 CFR 1.116(e). 			
9. The affidavit or other evidence filed after the date of filing entered because the affidavit or other evidence failed to o showing a good and sufficient reasons why it is necessary	vercome <u>all</u> rejections under appea	ıl and/or appellant fail:	s to provide a
10. ☐ The affidavit or other evidence is entered. An explanation REQUEST FOR RECONSIDERATION/OTHER	n of the status of the claims after er	ntry is below or attach	ed.
 The request for reconsideration has been considered but See Continuation Sheet. 	t does NOT place the application in	condition for allowan	ce because:
12.	PTO/SB/08) Paper No(s)		
	/DAVID VU/ Primary Examiner, Art U	nit 2818	

Continuation of 11. does NOT place the application in condition for allowance because:

Regarding the applicant's statement that step of cleaning the CVD chamber using a fluorine-containing gas is inherent; the applicant has provided no evidence that this step is inherent, the applicant's position is that when this cleaning step is done then fluorine is present in the gate insulating film. The examiner respectfully states that the applicant has stated that this step is required between subsequent CVD depositions but has not provided a showing that this cleaning step is required for the first time the CVD chamber is used to make the devices of the prior art and as such arguments cannot be construed as evidence. The examiner provided the Shimizu reference that does not perform the fluorine cleaning of the CVD chamber and alternatively provided the Robertson reference making a prima facie showing of obviousness that even if one were to do the cleaning step using fluorine gas between subsequent CVD depositions of silicon nitride that Robertson teaches the method of removing the any remaining fluorine residue and at the same time ensure that particulates remaining in the chamber do not fall onto the substrate, see specifically paragraph 8 of Robertson. Therefore removing any remaining fluorine residue and encapsulating the particulates as taught by Robertson between subsequent CVD steps of silicon nitride would therefore produce the thin film transistor not having fluorine in the gate insulating film.

Furthermore, it is noted that the applicant implies that the prior art references are substantially the same and producing the same results as the conventional description stated in applicant's specification at paragraphs 23 and 24, however there is no mention of these specific references in the applicant's specification.

The applicant also argues that Shimizu teaches a method that makes fabrication steps simple and the total fabrication cost is reduced and that Robertson teaches a complicated process that would make processing the device of Shimizu more complicated and costly. The examiner notes that the motivation for one skilled in the art to use the cleaning technique of Robertson for making the device as taught by Shimizu relies on making a more quailty product and as previously stated to remove the unwanted fluorine and particulates that can damage the device and to prevent unwanted threshold voltage shift, see specifically paragraph 7 of Robertson.